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PTO/SB/21 (09-04)

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<b>TRANSMITTAL FORM</b>  (to be used for all correspondence after initial filing)	Application Number	10/772,434	
	Filing Date	February 6, 2004	
	First Named Inventor	Ramachandran KRISHNASWAMY	
	Art Unit	2829	
	Examiner Name	Not Yet Assigned	
Total Number of Pages in This Submission	6 + 12 refs.	Attorney Docket Number	333772000800

ENCLOSURES (Check all that apply)		
<input type="checkbox"/> Fee Transmittal Form  <input type="checkbox"/> Fee Attached  <input type="checkbox"/> Amendment/Reply  <input type="checkbox"/> After Final  <input type="checkbox"/> Affidavits/declaration(s)  <input type="checkbox"/> Extension of Time Request  <input type="checkbox"/> Express Abandonment Request  <input checked="" type="checkbox"/> Information Disclosure Statement (3 pages)  <input type="checkbox"/> Certified Copy of Priority Document(s)  <input type="checkbox"/> Reply to Missing Parts/ Incomplete Application  <input type="checkbox"/> Reply to Missing Parts under 37 CFR 1.52 or 1.53	<input type="checkbox"/> Drawing(s)  <input type="checkbox"/> Licensing-related Papers  <input type="checkbox"/> Petition  <input type="checkbox"/> Petition to Convert to a Provisional Application  <input type="checkbox"/> Power of Attorney, Revocation Change of Correspondence Address  <input type="checkbox"/> Terminal Disclaimer  <input type="checkbox"/> Request for Refund  <input type="checkbox"/> CD, Number of CD(s) _____  <input type="checkbox"/> Landscape Table on CD	<input type="checkbox"/> After Allowance Communication to TC  <input type="checkbox"/> Appeal Communication to Board of Appeals and Interferences  <input type="checkbox"/> Appeal Communication to TC (Appeal Notice, Brief, Reply Brief)  <input type="checkbox"/> Proprietary Information  <input type="checkbox"/> Status Letter  <input checked="" type="checkbox"/> Other Enclosure(s) (please identify below): Form PTO/SB/08a/b + copy (2 pages) Twelve (12) Cited References Return Receipt Postcard
<b>Remarks</b>		

SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT			
Firm Name	MORRISON & FOERSTER LLP (Customer No. 25226)		
Signature			
Printed name	Thomas Chan		
Date	September 20, 2005	Reg. No.	51,543

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as Express Mail, Airbill No. EV595534704US, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date shown below.

Dated: September 20, 2005

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Dated: September 20, 2005 Signature: 

(Georgina Matos)

Patent

Docket No. 333772000800

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:  
Ramachandran KRISHNASWAMY et al.

Serial No.: 10/772,434

Filing Date: February 6, 2004

For: METHOD AND STRUCTURE TO  
DEVELOP A TEST PROGRAM FOR  
INTEGRATED CIRCUITS

Examiner: Not Yet Assigned

Group Art Unit: 2829

**SUPPLEMENTAL INFORMATION DISCLOSURE  
STATEMENT UNDER 37 C.F.R. § 1.97 & 1.98**

MS Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Dear Sir:

Pursuant to 37 C.F.R. §1.97 and § 1.98, Applicants submit for consideration in the above-identified application the documents listed on the attached Form PTO/SB/08a/b. Copies of foreign documents and non-patent literature are submitted herewith. The Examiner is requested to make these documents of record.

This Supplemental Information Disclosure Statement is submitted:

- ☐ With the application; accordingly, no fee or separate requirements are required.
- ☐ Before the mailing of a first Office Action after the filing of a Request for Continued Examination under § 1.114. However, if applicable, a certification under 37 C.F.R. § 1.97 (e)(1) has been provided.

- ☒ Within three months of the application filing date or before mailing of a first Office Action on the merits; accordingly, no fee or separate requirements are required. However, if applicable, a certification under 37 C.F.R. § 1.97 (e)(1) has been provided.
- ☐ After receipt of a first Office Action on the merits but before mailing of a final Office Action or Notice of Allowance.
- ☐ A fee is required. A check in the amount of \_\_ is enclosed.
- ☐ A fee is required. Accordingly, a Fee Transmittal form (PTO/SB/17) is attached to this submission in duplicate.
- ☐ A Certification under 37 C.F.R. § 1.97(e) is provided above; accordingly, no fee is believed to be due.
- ☐ After mailing of a final Office Action or Notice of Allowance, but before payment of the issue fee.
- ☐ A Certification under 37 C.F.R. § 1.97(e) is provided above and a check in the amount of \_\_ is enclosed.
- ☐ A Certification under 37 C.F.R. § 1.97(e) is provided above and a Fee Transmittal form (PTO/SB/17 is attached to this submission in duplicate.)

Applicants would appreciate the Examiner initialing and returning the Form PTO/SB/08a/b, indicating that the information has been considered and made of record herein.

The information contained in this Supplemental Information Disclosure Statement under 37 C.F.R. § 1.97 and § 1.98 is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

In the unlikely event that the transmittal form is separated from this document and the Patent and Trademark Office determines that an extension and/or other relief (such as payment of a fee under 37 C.F.R. § 1.17 (p)) is required, Applicants petition for any required relief including extensions of time and authorize the Commissioner to charge the cost of such petition and/or other

Application Serial No. 10/772,434

Patent  
Docket No. 333772000800

fees due in connection with the filing of this document to **Deposit Account No. 03-1952**  
referencing 333772000800.

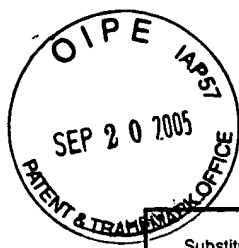
Dated: September 20, 2005

Respectfully submitted,

By 

Thomas Chan

Registration No.: 51,543  
MORRISON & FOERSTER LLP  
755 Page Mill Road  
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ALTERNATIVE TO PTO/SB/08a/b (07-05)

Substitute for form 1449/PTO				<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>				Application Number	10/772,434
				Filing Date	February 6, 2004
				First Named Inventor	Ramachandran KRISHNASWAMY
				Art Unit	2829
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	333772000800

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1.	US-2003/0005375-A1	01-02-2003	Krech, Jr. et al.	
	2.	US-2005/0154551-A1	07-14-2005	Pramanick et al.	
	3.	US-2005/0022087-A1	01-27-2005	Pramanick et al.	
	4.	US-6,028,439-A	02-22-2000	Arkin et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	MM-DD-YYYY			
	5.	WO-2004/072669-A1	08-26-2004	Advantest Corporation		
	6.	WO-2004/072670-A1	08-26-2004	Adventest Corporation		

\*EXAMINER: Initial if information considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author ( in CAPITAL LETTERS), title of the article ( when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	7.	Chang, E. et al. (1998). "A Scalable Architecture for VLSI Test," <i>IEEE, Proceedings International Test Conference 1998</i> , Washington, DC. Paper 20.2, pp. 500-506.	
	8.	Conti, D. R. (2002). "Mission Impossible? Open Architecture ATE," <i>IEEE, Proceedings International Test Conference 2002</i> , Washington, DC. Panel P5.1, p 1207.	
	9.	Evans, A.C. (1999). "Applications of Semiconductor Test Economics, and Multisite Testing to Lower Cost of Test," <i>IEEE, Proceedings International Test Conference 1999</i> , Washington, DC. Paper 5.2, pp. 113-123.	
	10.	Fan, D. et al. (2003). "Case Study - Using STIL as Test Pattern Language," <i>NPTest, Inc. LLC, ITC International Test Conference</i> , Paper 32:3, pp. 811-817.	
	11.	Mirizzi, D.J. et al. (1993). "Implementation of Parrallelsite Test on an 8-Bit Configurable Microcontroller," <i>IEEE, Proceedings International Test Conference 1993</i> , Washington, DC. Paper 8.3, pp. 226-235.	
	12.	Perez, S.M. (2002). "The Consequences of an Open ATE Architecture," <i>IEEE, Proceedings International Test Conference 2002</i> , Washington, DC. Panel P5.4, p 1210.	
	13.	Perez, S.M. et al. (July 16, 2003). "Open Architecture Test System: The New Frontier," <i>28th IEEE/CPMI/SEMI International Electronics Manufacturing Technology Symposium</i> , San Jose, CA, July 16-18, 2003, pp. 211-214.	
	14.	Schoettmer, U. et al. (1995). "Challenging the 'High Performance - High Cost' Paradigm in Test," <i>IEEE, Proceedings International Test Conference 1995</i> , Washington, DC. Paper 37.1, pp. 870-879.	
	15.	Simpson, W.R. (1995). "Cutting the Cost of Test; the Value-added Way," <i>IEEE, Proceedings International Test Conference 1995</i> , Washington, DC. Paper 41.2, p. 921.	
	16.	West, B.G. (2002). "Open ATE Architecture: Key Challenges," <i>IEEE, Proceedings International Test Conference 2002</i> , Washington, DC. Panel P5.6, p. 1212.	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature		Date Considered	
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pa- 1010138



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SHANGHAI, HONG KONG,  
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September 16, 2005

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370-0178  
JAPAN

Re: U.S. Patent Application Serial No. 10/772,434  
For: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR  
INTEGRATED CIRCUITS

By: Ramachandran KRISHNASWAMY et al.  
Our Reference: 33377-20008.00

Dear Mr. Takechi:

Enclosed for your files is a copy of a Supplemental Information Disclosure Statement which was filed in the U.S. Patent and Trademark Office on September 20, 2005 for the above-identified application.

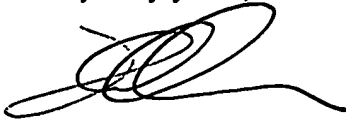
As you know, U.S. law places a continuing duty on inventors, their attorneys and agents who prepare and prosecute their patent application, and the application's assignee to the extent that they are associated with the prosecution, to disclose to the PTO information of which they are aware that may be material to the examination of the application.

Accordingly, if you become aware of additional references or other information during the pendency of this application, e.g., publications or patents, possible prior public uses or sales of the invention in the United States, prior invention by another, knowledge derived from others in making the invention, or inventorship disputes, please notify us.

Mr. Yoshinobu Takechi  
September 16, 2005  
Page Two

The American Inventors Protection Act of 1999 makes available to patent applicants extensions of the patent term where the PTO causes delays during examination for cases filed on or after May 29, 2000. The PTO defines the types of delays giving rise to such extensions of time. However, any potential term extensions caused by PTO delay are offset or reduced by any delays caused by an applicant's "failure to engage in reasonable efforts to conclude prosecution." Accordingly, it is preferable to promptly file any further IDS that may be required.

Very truly yours,

A handwritten signature in black ink, appearing to be 'Thomas Chan', with a stylized, cursive script.

Thomas Chan

TCC3/kck2  
Enclosure

cc: Mr. Neils Markert